BLP021N10
MOSFET

1. Description

BLP021N10, the N-channel Enhanced Power MOSFETs, is obtained by advanced double trench II technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. This is suitable device for BMS and high current switching applications.
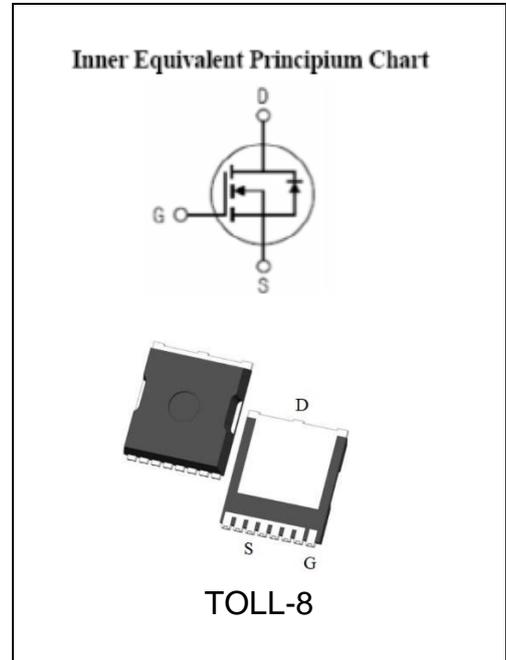
KEY CHARACTERISTICS

Parameter	Value	Unit
V_{DSS}	100	V
I_D	292	A
$R_{DS(on).typ}$	1.6	mΩ

FEATURES
- Fast Switching
- Low On-Resistance
- Low Gate Charge
- Low Reverse transfer capacitances
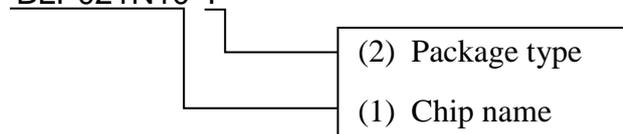- High avalanche ruggedness
- RoHS product

APPLICATIONS
- BMS
- High current switching applications

Inner Equivalent Principium Chart

TOLL-8

ORDERING INFORMATION

Ordering Codes	Product Code	Package	Device Marking	Packing
BLP021N10-T	BLP021N10	TOLL-8	P021N10	Reel

BLP021N10-T

(2) Package type
(1) Chip name

(1) BLP021N10：2.1mΩ/100V
(2) T：TOLL-8

XXXXX：Device Marking

XXXXX
YYWW ZZ
SSSSS

YYWW：Year&Week

ZZ：Assembly Code

SSSSS：Lot Code

2. ABSOLUTE RATINGS

at T_C=25°C，unless otherwise specified

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-Source Voltage	100	V
I_D	Continuous Drain Current, Silicon Limited	292	A
	Continuous Drain Current, Package Limited	360	A
	Continuous Drain Current @T_C=100°C, Silicon Limited	184.6	A
I_{DM} Note1	Pulsed Drain Current	1168	A
V_{GS}	Gate-Source Voltage	±20	V
E_{AS} Note2	Avalanche Energy	1225	mJ
P_D	Power Dissipation	312.5	W
	Derating Factor above 25°C	2.5	W/°C
T_J，T_{stg}	Operating Junction and Storage Temperature Range	150，−55 to 150	°C
T_L	Maximum Temperature for Soldering	260	°C

Note1：Repetitive Rating：Pulse width limited by maximum junction temperature

Note2：L=0.5mH, Ias=70A, Start T_J=25°C

3. Thermal characteristics

Symbol	Parameter	Max	Units
$R_{\theta JC}$	thermal resistance, Junction-Case	0.4	°C/W
$R_{\theta JA}$	thermal resistance, Junction-Ambient	62.5	°C/W

4. Electrical Characteristics

at T_C=25°C, unless otherwise specified

OFF Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
V_{DSS}	Drain-Source Breakdown Voltage	V_{GS}=0V, I_D=250μA	100	110	--	V
I_{DSS}	Drain-Source Leakage Current	V_{DS}=100V, V_{GS}=0V	--	--	1	μA
		V_{DS}=80V, V_{GS}=0V @T_C=125°C	--	--	100	μA
$I_{GSS(F)}$	Gate-Source Forward Leakage	V_{GS}=+20V	--	--	100	nA
$I_{GSS(R)}$	Gate-Source Reverse Leakage	V_{GS}=-20V	--	--	-100	nA

ON Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$R_{DS(on)}$	Drain-Source On-Resistance	$V_{GS}=10V$, $I_D=50A$	--	1.6	2.1	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2	3	4	V
Pulse width tp≤300µs, δ≤2%						

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
C_{iss}	Input Capacitance	$V_{DS}=50V$, $V_{GS}=0$, f=1MHz	--	11132	--	pF
C_{oss}	Output Capacitance		--	2780	--	
C_{rss}	Reverse Transfer Capacitance		--	532	--	
Q_g	Total Gate Charge	$V_{DD}=50V$, $I_D=100A$, $V_{GS}=10V$	--	168	--	nC
Q_{gs}	Gate-Source charge		--	59	--	
Q_{gd}	Gate-Drain charge		--	35	--	
R_G	Gate resistance	$V_{GS}=0$, $V_{DS}=0$		1		Ω

Switching Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=50V$, $I_D=100A$, $V_{GS}=10V$, $R_G=1.6\Omega$, Resistive Load	--	59	--	ns
t_r	Rise Time		--	66	--	
$t_{d(off)}$	Turn-Off Delay Time		--	185	--	
t_f	Fall Time		--	95	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
I_S	Continuous Source Current		--	--	292	A
I_{SM}	Maximum Pulsed Current		--	--	1168	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0V$, $I_S=50A$	--	--	1.2	V
T_{rr}	Reverse Recovery Time	$I_s=100A$, $V_{GS}=0$, di/dt=100A/us	--	66	--	ns
Q_{rr}	Reverse Recovery Charge		--	200	--	nC

5. Characteristics Curves
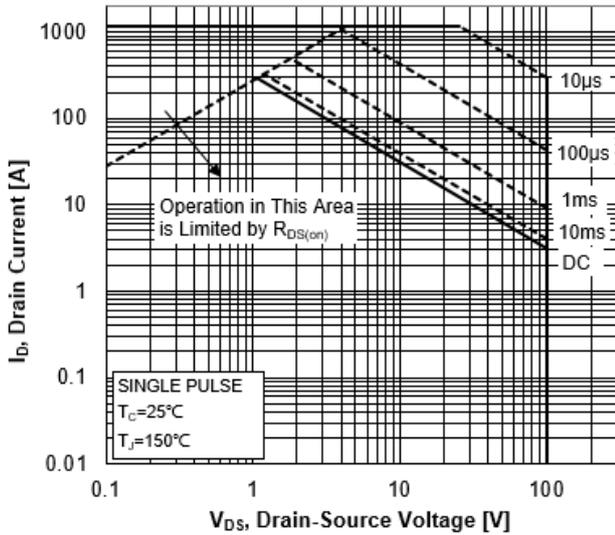
Figure 1. Safe Operating Area

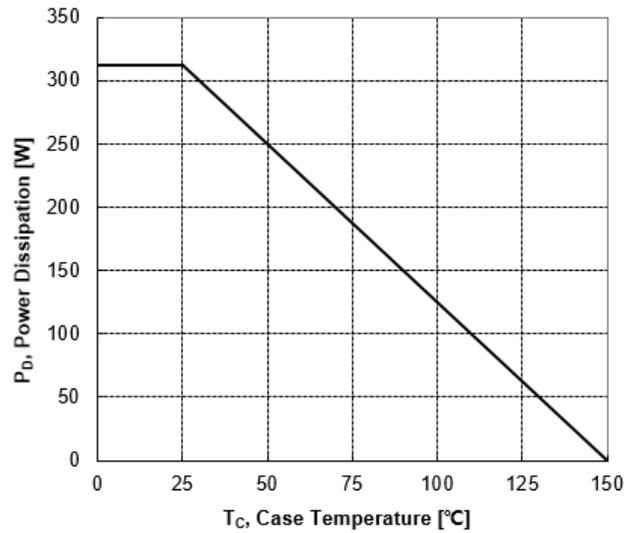### Figure 2. Maximum Power Dissipation vs Case Temperature

Figure 3. Maximum Continuous Drain Current vs Case Temperature
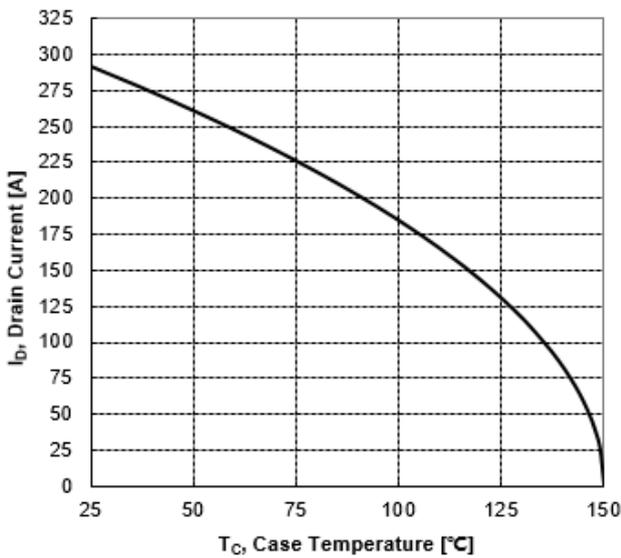

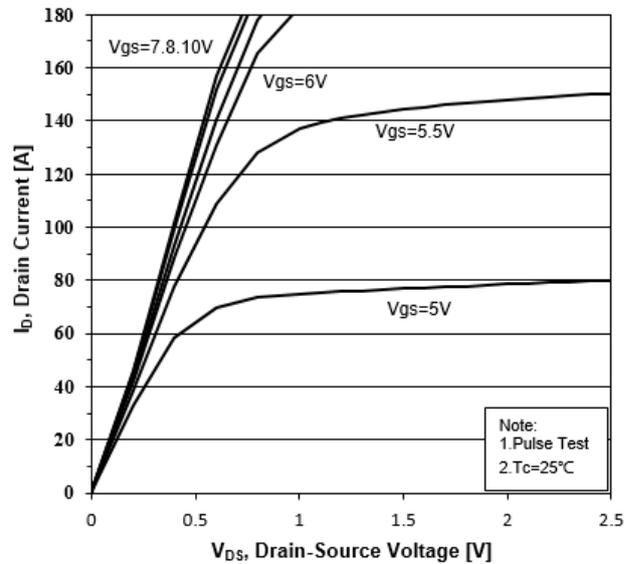### Figure 4. Typical Output Characteristics
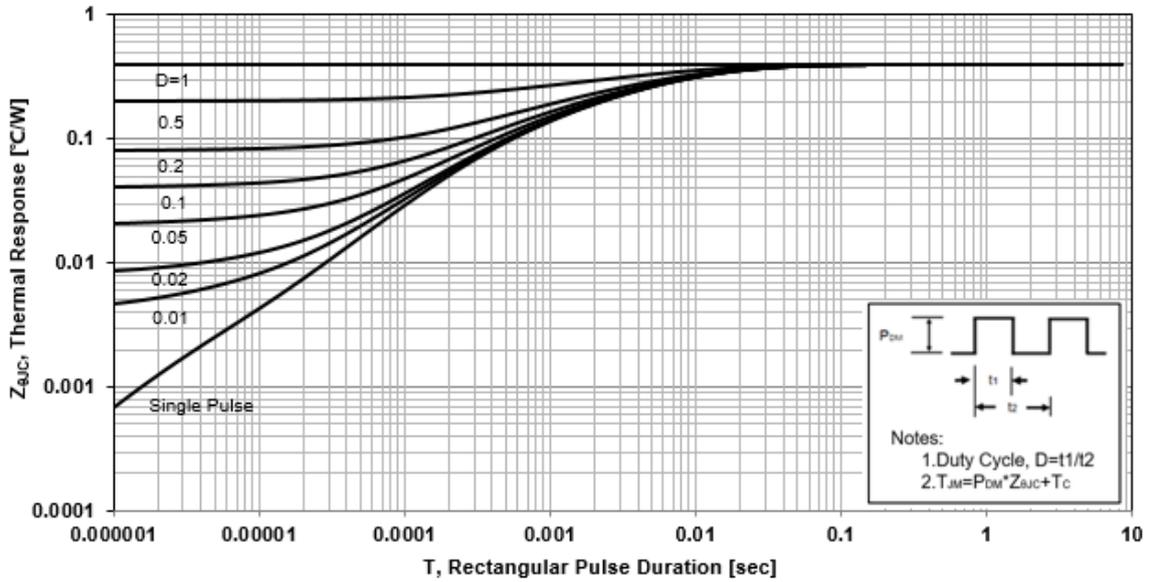
Figure 5. Transient Thermal Impedance

Figure 6. Typical Transfer Characteristics

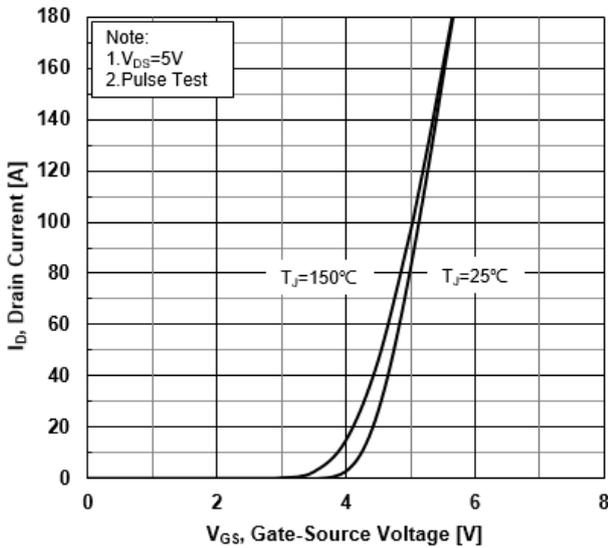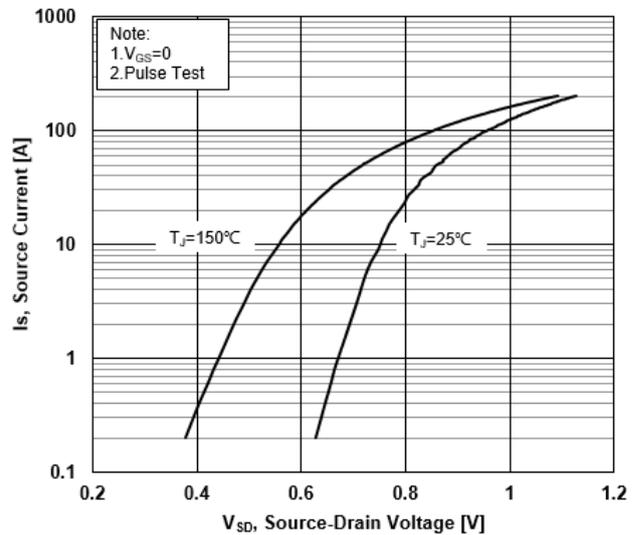## Figure 7. Source-Drain Diode Forward Characteristics
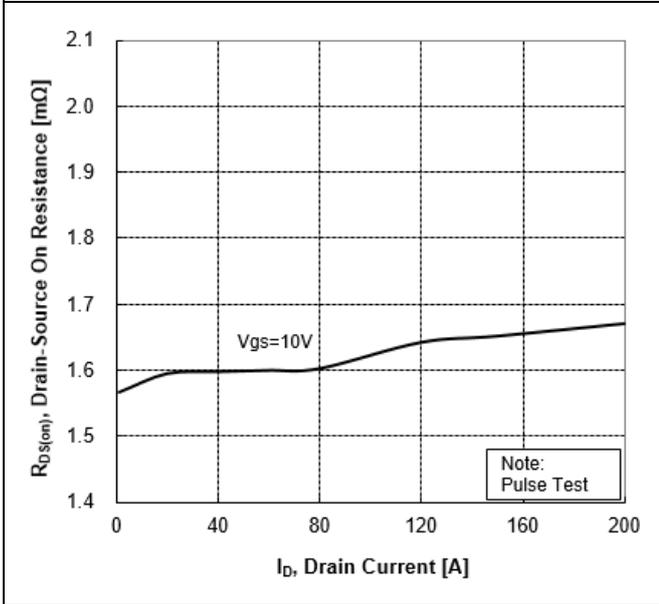
Figure 8. Drain-Source On-Resistance vs Drain Current

Figure 9. Normalized On-Resistance vs Junction Temperature
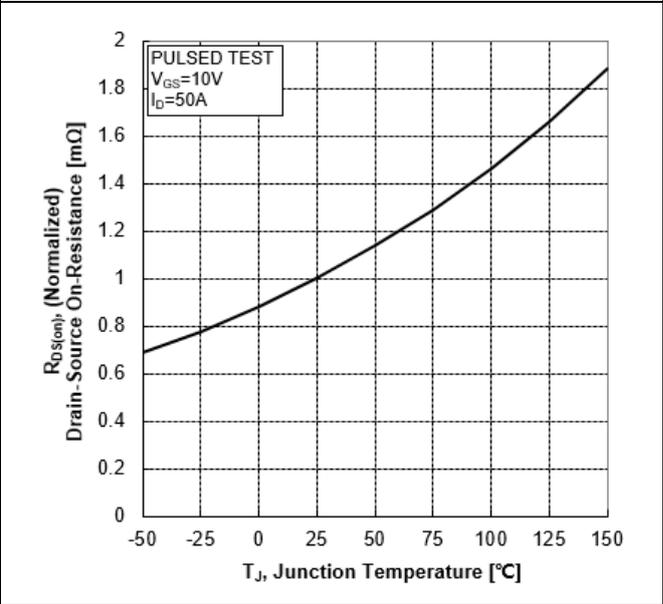
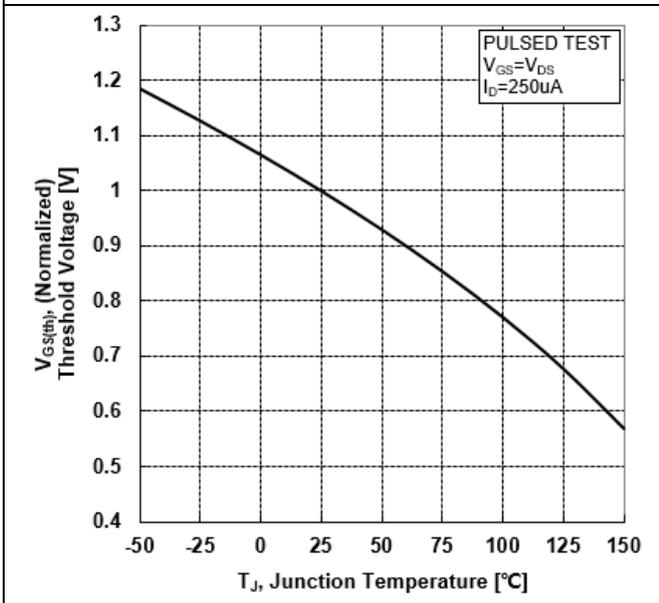### Figure 10. Normalized Threshold Voltage vs Junction Temperature

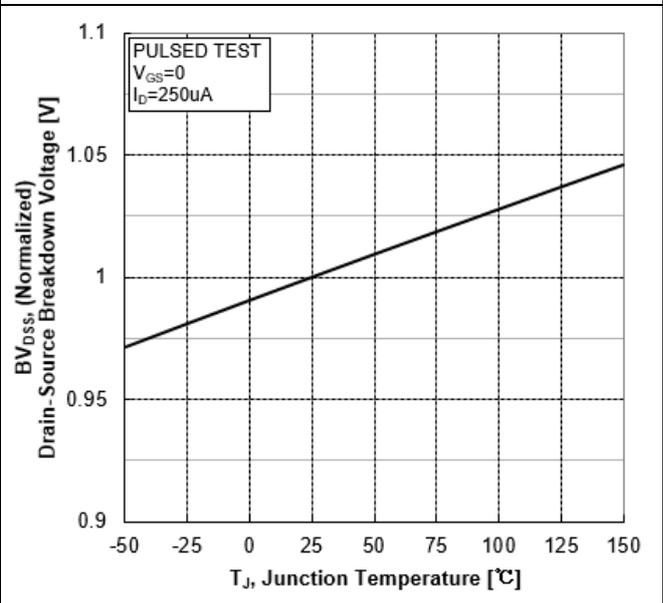### Figure 11. Normalized Breakdown Voltage vs Junction Temperature
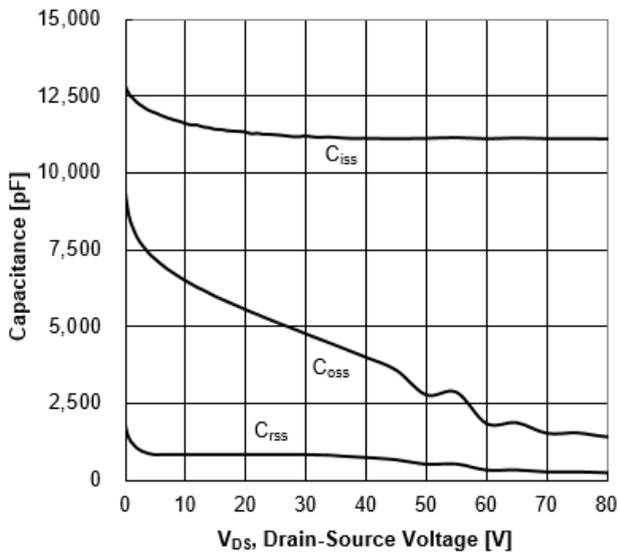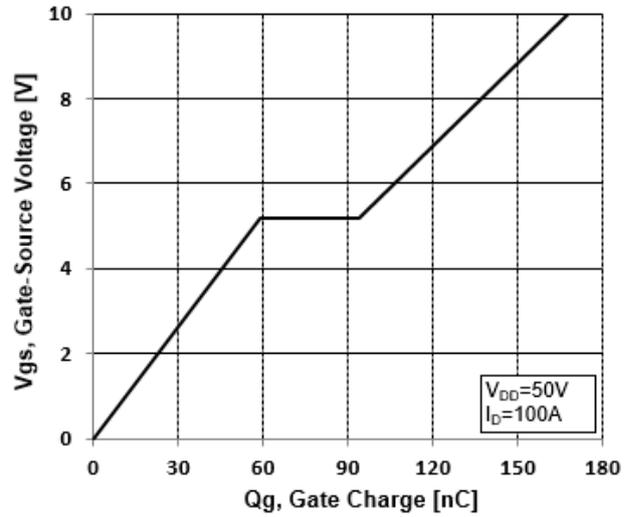
Figure 12. Capacitance Characteristics	Figure 13. Typical Gate Charge vs Gate-Source Voltage

6. Test Circuit and Waveform
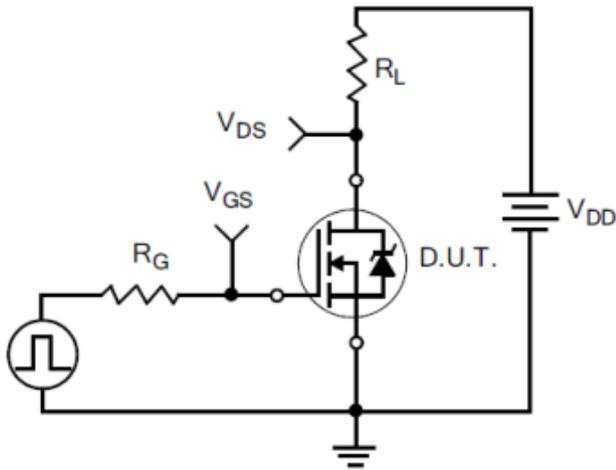
Figure 14. Resistive Switching Test Circuit	Figure 15. Resistive Switching Waveforms

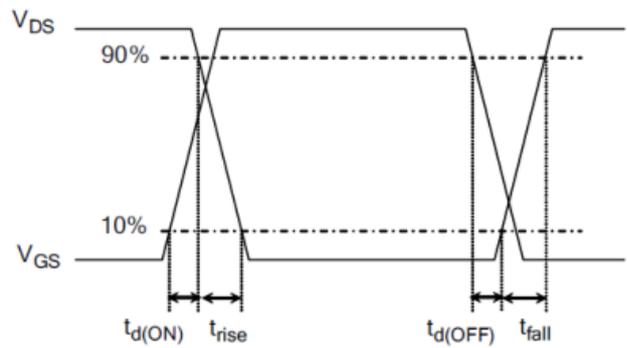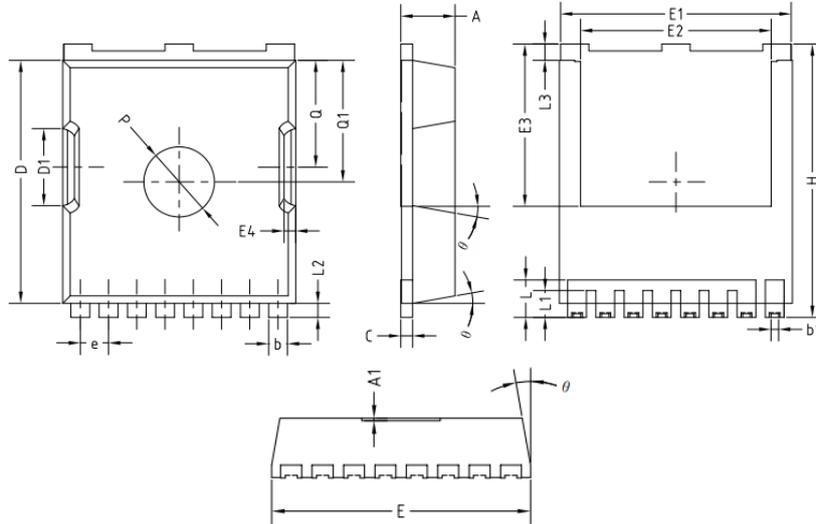| Figure 16. Gate Charge Test Circuit	Figure 17. Gate Charge Waveforms
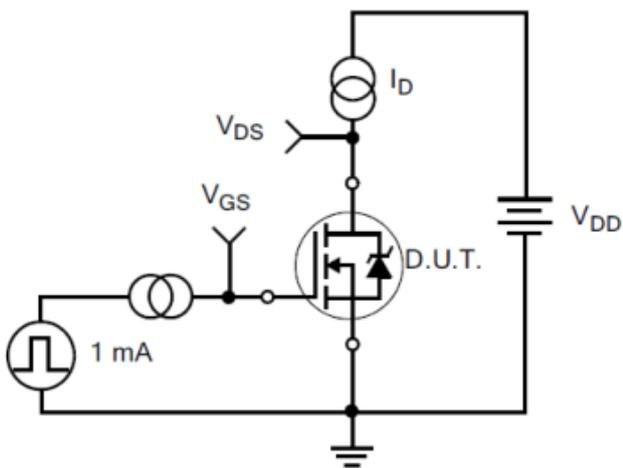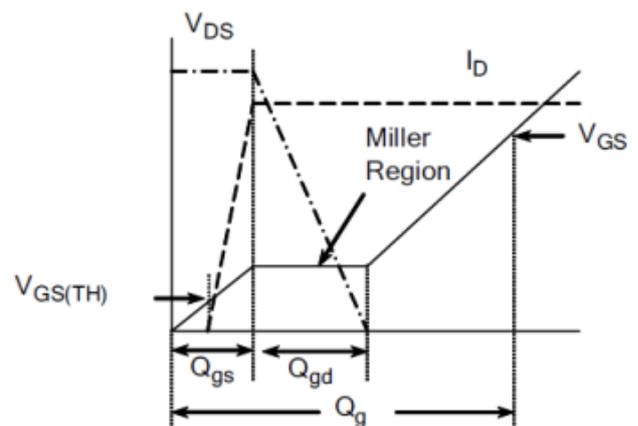
Figure 18. Diode Reverse Recovery Test Circuit	Figure 19. Diode Reverse Recovery Waveform

Figure 20. Unclamped Inductive Switching Test Circuit	Figure 21. Unclamped Inductive Switching Waveform

$$E_{AS} = \frac{I_{AS}^2 L}{2}$$

7. Package Description

TOLL-8

Symbols	MIN	NOM	MAX
A	2.15	2.3	2.45
A1		0.1REF	
b	0.6	0.75	0.9
b1		0.4REF	
C		0.5REF	
D	10.2	10.5	10.8
D1	2.8	3.2	3.6
E	9.7	9.9	10.1
E2		8.5REF	
E1	9.6	9.8	10
e		1.2REF	
H	11.5	11.75	12
E3		7REF	
E4		0.6REF	
Q		4.5REF	
Q1		5.2REF	
L	1	1.5	2
L3	0.5	0.7	0.9
L2	0.4	0.6	0.8
L1		1.1REF	
P	2	3	4
θ	7°	9°	12°

NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.

2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.

3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.

4. Shanghai Belling reserves the right to make changes in this specification sheet and is subject to change without prior notice.

CONTACT:

上海贝岭股份有限公司

地址：上海市宜山路 810 号

邮编：200233

联系方式：https://www.belling.com.cn/contact.html